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COMMENTED VERSION

Metoder för accelererad provning av produkter

Methods for product accelerated testing

En så kallad "Commented Version" (CMV) innehåller både den fastställda IEC-standarden och en kommenterad och ändringsmarkerad standard. Alla tillägg och borttagningar sedan den tidigare utgåvan är markerade med färg. Med en CMV sparar du mycket tid när du ska identifiera och förklara aktuella ändringar i standarden. SEK Svensk Elstandard kan bara ge ut CMV i de fall den finns tillgänglig från IEC.



IEC 62506

Edition 2.0 2023-11
COMMENTED VERSION

INTERNATIONAL STANDARD



Methods for product accelerated testing

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

ICS 03.120.01, 21.020

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

METHODS FOR PRODUCT ACCELERATED TESTING

FOREWORD

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This commented version (CMV) of the official standard IEC 62506:2023 edition 2.0 allows the user to identify the changes made to the previous IEC 62506:2013 edition 1.0. Furthermore, comments from IEC TC 56 experts are provided to explain the reasons of the most relevant changes, or to clarify any part of the content.

A vertical bar appears in the margin wherever a change has been made. Additions are in green text, deletions are in strikethrough red text. Experts' comments are identified by a blue-background number. Mouse over a number to display a pop-up note with the comment.

This publication contains the CMV and the official standard. The full list of comments is available at the end of the CMV.

IEC 62506 has been prepared by IEC technical committee 56: Dependability. It is an International Standard.

This second edition cancels and replaces the first edition published in 2013. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) references have been updated;
- b) symbols have been revised;
- c) errors in 5.7.2.3 and Annex B, mainly, have been corrected;
- d) calculation errors in the examples of Annex B and Annex F have been corrected.

The text of this International Standard is based on the following documents:

Draft	Report on voting
56/2000/FDIS	56/2016/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn, or
- revised.

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INTRODUCTION

Many reliability or failure investigation test methods have been developed and most of them are currently in use. These methods are used to either determine product reliability or to identify potential product failure modes, and have been considered effective as demonstrations of reliability:

- fixed duration,
- sequential probability ratio,
- reliability growth tests,
- tests to failure, etc.

Such tests, although very useful, are usually lengthy, especially when the product reliability that has to be demonstrated is high. The reduction in time-to-market periods as well as competitive product cost, increase the need for efficient and effective accelerated testing. Here, the tests are shortened through the application of increased stress levels or by increasing the speed of application of repetitive stresses, thus facilitating a quicker assessment and growth of product reliability through failure mode discovery and mitigation.

There are two distinctly different approaches to reliability activities:

- the first approach verifies, through analysis and testing, that there are no potential failure modes in the product that are likely to be activated during the expected life time of the product under the expected operating conditions and usage profile;
- the second approach estimates how many failures can be expected after a given time under the expected operating conditions and usage profile.

Accelerated testing is a method appropriate for both cases, but used quite differently. The first approach is associated with qualitative accelerated testing, where the goal is identification of potential faults that eventually ~~might~~ can result in product field failures. The second approach is associated with quantitative accelerated testing where the product reliability may be estimated based on the results of accelerated simulation testing that can be related back to the use of the environment and usage profile.

Accelerated testing can be applied to multiple levels of items containing hardware ~~or~~ and software. Different types of reliability testing, such as fixed duration, sequential test-to-failure, success test, reliability demonstration, or reliability growth ~~or~~ improvement tests can be candidates for accelerated methods. This document provides guidance on selected, commonly used accelerated test types. This document should be used in conjunction with statistical test plan standards such as IEC 61123, IEC 61124, IEC 61649 and IEC 61710.

The relative merits of various methods and their individual or combined applicability in evaluating a given system or item, should be reviewed by the product design team (including ~~dependability~~ reliability engineering) prior to selection of a specific test method or a combination of methods. For each method, consideration should also be given to the test time, results produced, credibility of the results, data required to perform meaningful analysis, life cycle cost impact, complexity of analysis and other identified factors.

In this document the term "item" is used as defined in IEC 60050-192 covering physical products as well as software. Services and people are however not covered by this document.

METHODS FOR PRODUCT ACCELERATED TESTING

1 Scope

This document provides guidance on the application of various accelerated test techniques for measurement or improvement of ~~product~~ item reliability. Identification of potential failure modes that ~~could~~ can be experienced in the use of ~~a product/~~ an item and their mitigation is instrumental to ensure dependability of an item.

The object of the methods is to either identify potential design weakness or provide information on item ~~dependability~~ reliability, or to achieve necessary reliability/ and availability improvement, all within a compressed or accelerated period of time. This document addresses accelerated testing of non-repairable and repairable systems. It can be used for probability ratio sequential tests, fixed duration tests and reliability improvement/growth tests, where the measure of reliability ~~may~~ can differ from the standard probability of failure occurrence.

This document also extends to present accelerated testing or production screening methods that would identify weakness introduced into the ~~product~~ item by manufacturing error, which ~~could~~ can compromise ~~product dependability~~ item reliability. Services and people are however not covered by this document.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-192 – *International Electrotechnical Vocabulary (IEV) – Part 192: Dependability*, available at <http://www.electropedia.org>

~~IEC 60068 (all parts), Environmental testing~~

~~IEC 60300-3-1:2003, Dependability management – Part 3-1: Application guide – Analysis techniques for dependability – Guide on methodology~~

IEC 60300-3-5, *Dependability management – Part 3-5: Application guide – Reliability test conditions and statistical test principles*

IEC 60605-2, *Equipment reliability testing – Part 2: Design of test cycles*

IEC 60721 (all parts), *Classification of environmental conditions*

~~IEC 61014:2003, Programmes for reliability growth~~

IEC 61123:2019, *Reliability testing – Compliance test plans for success ratio*

IEC 61124:2012/2023, *Reliability testing – Compliance tests for constant failure rate and constant failure intensity*

~~IEC 61163-2, Reliability stress screening – Part 2: Electronic components~~

~~IEC 61164:2004, Reliability growth – Statistical test and estimation methods~~

IEC 61649:2008, Weibull analysis

IEC 61709, ~~Electronic~~ Electric components – Reliability – Reference conditions for failure rates and stress models for conversion

IEC 61710, Power law model – Goodness-of-fit tests and estimation methods

~~IEC 62303, Radiation protection instrumentation – Equipment for monitoring airborne tritium~~

~~IEC/TR 62380, Reliability data handbook – Universal model for reliability prediction of electronics components, PCBs and equipment~~

IEC 62429, Reliability growth – Stress testing for early failures in unique complex systems

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Metoder för accelererad provning av produkter

Methods for product accelerated testing

Som svensk standard gäller europastandarden EN IEC 62506:2023. Den svenska standarden innehåller den officiella engelska språkversionen av EN IEC 62506:2023.

Nationellt förord

Europastandarden EN IEC 62506:2023

består av:

- **europastandardens ikraftsättningsdokument**, utarbetat inom CENELEC
- **IEC 62506, Second edition, 2023 - Methods for product accelerated testing**

utarbetad inom International Electrotechnical Commission, IEC.

Tidigare fastställd svensk standard SS-EN 62506, utg 1:2014 med eventuella tillägg, ändringar och rättelser gäller ej fr o m 2026-12-12.

ICS 03.120.01; 21.020.00

Denna standard är fastställd av SEK Svensk Elstandard, som också kan lämna upplysningar om **sakinnehållet** i standarden.
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Det finns många fördelar med att ha gemensamma tekniska regler för bl a mätning, säkerhet och provning och för utförande, skötsel och dokumentation av elprodukter och elanläggningar.

Genom att utforma sådana standarder blir säkerhetsfordringar tydliga och utvecklingskostnaderna rimliga samtidigt som marknadens acceptans för produkten eller tjänsten ökar.

Många standarder inom elområdet beskriver tekniska lösningar och metoder som åstadkommer den elsäkerhet som föreskrivs av svenska myndigheter och av EU.

SEK är Sveriges röst i standardiseringsarbetet inom elområdet

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Du som vill dra nytta av dessa möjligheter är välkommen att kontakta SEKs kansli för mer information.

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English Version

**Methods for product accelerated testing
(IEC 62506:2023)**Méthodes d'essais accélérés de produits
(IEC 62506:2023)Verfahren für beschleunigte Produktprüfungen
(IEC 62506:2023)

This European Standard was approved by CENELEC on 2023-12-12. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

European foreword

The text of document 56/2000/FDIS, future edition 2 of IEC 62506, prepared by IEC/TC 56 "Dependability" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 62506:2023.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2024-09-12
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2026-12-12

This document supersedes EN 62506:2013 and all of its amendments and corrigenda (if any).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC shall not be held responsible for identifying any or all such patent rights.

Any feedback and questions on this document should be directed to the users' national committee. A complete listing of these bodies can be found on the CENELEC website.

Endorsement notice

The text of the International Standard IEC 62506:2023 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standard indicated:

- IEC 62740:2015 NOTE Approved as EN 62740:2015 (not modified)
- IEC 60812 NOTE Approved as EN IEC 60812
- IEC 61163-2 NOTE Approved as EN IEC 61163-2
- IEC 60300-3-4 NOTE Approved as EN IEC 60300-3-4
- IEC 60068 (series) NOTE Approved as EN 60068 (series)
- IEC 61014 NOTE Approved as EN 61014
- IEC 61163-1 NOTE Approved as EN 61163-1
- IEC 61164:2004 NOTE Approved as EN 61164:2004 (not modified)
- IEC 61125:2018 NOTE Approved as EN IEC 61125:2018 (not modified)

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cencenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-192	-	International electrotechnical vocabulary - Part 192: Dependability	-	-
IEC 60300-3-5	-	Dependability management - Part 3-5: Application guide - Reliability test conditions and statistical test principles	-	-
IEC 60605-2	-	Equipment reliability testing - Part 2: Design of test cycles	-	-
IEC 60721	series	Classification of environmental conditions	EN 60721	series
IEC 61123	2019	Reliability testing - Compliance test plans for success ratio	EN IEC 61123	2020
IEC 61124	2023	Reliability testing - Compliance tests for constant failure rate and constant failure intensity	EN IEC 61124	2023
IEC 61649	2008	Weibull analysis	EN 61649	2008
IEC 61709	-	Electric components - Reliability - Reference conditions for failure rates and stress models for conversion	EN 61709	-
IEC 61710	-	Power law model - Goodness-of-fit tests and estimation methods	EN 61710	-
IEC 62429	-	Reliability growth - Stress testing for early failures in unique complex systems	EN 62429	-



IEC 62506

Edition 2.0 2023-11

INTERNATIONAL STANDARD

NORME INTERNATIONALE



Methods for product accelerated testing

Méthodes d'essais accélérés de produits

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

METHODS FOR PRODUCT ACCELERATED TESTING**FOREWORD**

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This second edition cancels and replaces the first edition published in 2013. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) references have been updated;
- b) symbols have been revised;
- c) errors in 5.7.2.3 and Annex B, mainly, have been corrected;
- d) calculation errors in the examples of Annex B and Annex F have been corrected.

The text of this International Standard is based on the following documents:

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Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

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- reconfirmed,
- withdrawn, or
- revised.

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INTRODUCTION

Many reliability or failure investigation test methods have been developed and most of them are currently in use. These methods are used to either determine product reliability or to identify potential product failure modes, and have been considered effective as demonstrations of reliability:

- fixed duration,
- sequential probability ratio,
- reliability growth tests,
- tests to failure, etc.

Such tests, although very useful, are usually lengthy, especially when the product reliability that has to be demonstrated is high. The reduction in time-to-market periods as well as competitive product cost, increase the need for efficient and effective accelerated testing. Here, the tests are shortened through the application of increased stress levels or by increasing the speed of application of repetitive stresses, thus facilitating a quicker assessment and growth of product reliability through failure mode discovery and mitigation.

There are two distinctly different approaches to reliability activities:

- the first approach verifies, through analysis and testing, that there are no potential failure modes in the product that are likely to be activated during the expected life time of the product under the expected operating conditions and usage profile;
- the second approach estimates how many failures can be expected after a given time under the expected operating conditions and usage profile.

Accelerated testing is a method appropriate for both cases, but used quite differently. The first approach is associated with qualitative accelerated testing, where the goal is identification of potential faults that eventually can result in product field failures. The second approach is associated with quantitative accelerated testing where the product reliability may be estimated based on the results of accelerated simulation testing that can be related back to the use of the environment and usage profile.

Accelerated testing can be applied to multiple levels of items containing hardware and software. Different types of reliability testing, such as fixed duration, sequential test-to-failure, success test, reliability demonstration, or reliability growth or improvement tests can be candidates for accelerated methods. This document provides guidance on selected, commonly used accelerated test types. This document should be used in conjunction with statistical test plan standards such as IEC 61123, IEC 61124, IEC 61649 and IEC 61710.

The relative merits of various methods and their individual or combined applicability in evaluating a given system or item, should be reviewed by the product design team (including reliability engineering) prior to selection of a specific test method or a combination of methods. For each method, consideration should also be given to the test time, results produced, credibility of the results, data required to perform meaningful analysis, life cycle cost impact, complexity of analysis and other identified factors.

In this document the term "item" is used as defined in IEC 60050-192 covering physical products as well as software. Services and people are however not covered by this document.

METHODS FOR PRODUCT ACCELERATED TESTING

1 Scope

This document provides guidance on the application of various accelerated test techniques for measurement or improvement of item reliability. Identification of potential failure modes that can be experienced in the use of an item and their mitigation is instrumental to ensure dependability of an item.

The object of the methods is to either identify potential design weakness or provide information on item reliability, or to achieve necessary reliability and availability improvement, all within a compressed or accelerated period of time. This document addresses accelerated testing of non-repairable and repairable systems. It can be used for probability ratio sequential tests, fixed duration tests and reliability improvement/growth tests, where the measure of reliability can differ from the standard probability of failure occurrence.

This document also extends to present accelerated testing or production screening methods that would identify weakness introduced into the item by manufacturing error, which can compromise item reliability. Services and people are however not covered by this document.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-192 – *International Electrotechnical Vocabulary (IEV) – Part 192: Dependability*, available at <http://www.electropedia.org>

IEC 60300-3-5, *Dependability management – Part 3-5: Application guide – Reliability test conditions and statistical test principles*

IEC 60605-2, *Equipment reliability testing – Part 2: Design of test cycles*

IEC 60721 (all parts), *Classification of environmental conditions*

IEC 61123:2019, *Reliability testing – Compliance test plans for success ratio*

IEC 61124:2023, *Reliability testing – Compliance tests for constant failure rate and constant failure intensity*

IEC 61649:2008, *Weibull analysis*

IEC 61709, *Electric components – Reliability – Reference conditions for failure rates and stress models for conversion*

IEC 61710, *Power law model – Goodness-of-fit tests and estimation methods*

IEC 62429, *Reliability growth – Stress testing for early failures in unique complex systems*